

# LORLIN<sup>®</sup>

## TEST SYSTEMS



Lorlin Reconditioned Impact Series Test Systems check and verify the critical parameters of Small Signal and Power Discrete Semiconductors with a maximum degree of accuracy, yielding repeatable results and ensuring the highest confidence level attainable.

Lorlin Reconditioned Systems start under \$19,900 depending on the configuration and requirements. The Lorlin Windows Software is by far the most powerful and functional tool offering the user complete control over the desired test selections, options, sorting, binning, screening and numerous data reporting methods.

Lorlin also offers custom design engineering services, solutions and integration of many types of external equipment to meet your needs. The high performance reconditioned systems offer easy to use Windows for test routine creation, operation, and data views.

Transistors  
IGBTs  
Diodes  
Rectifiers  
Bridges  
Zeners  
Darlingtons  
FETs  
MOSFETs  
JFETs  
SCRs  
Triacs  
Optos  
Arrays  
Small Signal  
Power Devices  
Hybrid Modules  
Dual, Quad and Octal

## Reconditioned Test Systems

### BENEFITS

Test, Sort, Classify, Grade Discrete Semiconductors  
Affordably Priced Systems, Starting under \$19,900  
Warranty, Installation, Training Available  
Flexible Design - Easily Configurable - Expandability

### FEATURES

600 to 2000 Volts / 20 to 500 Amps  
The Most Powerful Windows Testing Software  
Auto/Manual Testing with Handlers and Probers  
Extensive Test Parameter Library - Easy to Use

### PERFORMANCE

Diagnostics Program Verify System Integrity  
System Calibration Software Ensures Accuracy  
Standard Leakage Resolution to 5 Pico Amps  
Test by Branch and Sort Modes Run Concurrently

**Lorlin Test Systems, Inc.**

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Lorlin Reconditioned Testers can be configured for most all applications offering cost effective test solutions with high performance results.

The test system can be used for incoming inspection, quality assurance, high reliability, component characterization, final test, and wafer probe.

System measurement techniques, refined and proven by over 50 years combined with the most powerful software in the industry make Lorlin Test Systems a perfect choice.

**Contact us Today for Pricing and Information**



**The Most Advanced Discrete  
Test Systems Available**



1. Accuracy does not include the tag error and vary on test performed.
2. Higher ranges may affect resolution and accuracy specifications.
3. Requires an external high voltage and/or high current supply

## Reconditioned Systems

### System Specifications

FEATURE	RANGE	RESOLUTION	ACCURACY
Voltage Measurements	0-600 V 600-2000 V <sup>2</sup>	0.5 mV	0.5% <sup>1</sup>
Current Measurements	0-20 A 20-500A <sup>2</sup>	5 pA	0.5% <sup>1</sup>
Expands to 5 Test Stations and PCs	Rack Mounted, and Desktop	N/A	N/A
High Voltage/High Current Multiplex X4	2000 Volts 200 Amps	See Above	See Above

### Test Parameters

TEST TYPE	TYPICAL PARAMETERS
Leakage	IR, ICE(O,S,V,R,X), IEBO, IC IDGO, IGSO, IDSO (O,S,R,X,V), IGSS, IGV, IGDO, IDSX, ISDX, ISVI, IGI, VGSI, VTHI
Breakdown	BVCBO, BVEBO, BVCE(O, S, V, R, X) <sup>2</sup> BVR, BVZ, BVDGO, BVGSO, BVDS ( O,S,R,X,V)
On State	HFE IB, HFE, DHFE, VCESAT, VBESAT, VBEF, VBCF, VRE, VBEON, VF, VZ, VGSF, VGDF, VGS, VDS, VDSON, RDSON, IDON, VTH, ZZ(T,K)
Gain	HFE, I+HFE IB, DHFE, AC I + HFE, AC HIB, GM
Scr/Triac	IAKR, IAKF, IGKO, BVAKR, IH, BVAKF, BVGKO, IGT, VGT, TH, IL, VON

### System and Standard Options

PRODUCT DESCRIPTION	MODEL	OPTIONAL	COMMENTS
<b>Double Impact Systems</b>			
Double Impact Base System	DI-700	RACK PC AND VIDEO CONSOLE	Up to 5 Stations and PCs
Standard Station 600V/20A	OTS-100	100 A <sup>3</sup>	Requires Supply
2 KV Station with Built In Supply	HVS-102	100A <sup>3</sup>	Requires Supply
200 A Station with Built In Supply	OTS-300	OTS-340 400A	HCS-500 500A
2KV Multiplex Test Station Up to 4 per System	OTS-201 OTS-221	100 A 160-200 A	Requires Supply <sup>3</sup> Requires Supply <sup>3</sup>
Power Fet Option	FET-101	80 V Gate Supply	Plug In Option
Scr/Triac Option	SCR-100	User Adjustable	Plug In Option
<sup>1</sup> High Voltage Supply	HVS-201 High Voltage Supply, Multiplexes to 4 Stations		
<sup>2</sup> High Current Supply	HCM-201 High Current Supply, Multiplexes to 4 Stations		

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